

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 856063.720D1	APPLICATION NO. 10/615,961
		APPLICANT Raffaele Zambrano	
		FILING DATE July 8, 2003	GROUP ART UNIT 2818

INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
TH	AA	5,475,248	12/12/95	Takenaka	257	295	
	AB	5,481,490	01/02/96	Watanabe et al.	365	145	
	AC	5,578,867	11/26/96	Argos, Jr. et al.	257	632	
	AD	5,638,319	06/10/97	Onishi et al.	365	145	
	AE	5,716,875	02/10/98	Jones, Jr. et al.	438	3	
	AF	5,750,419	05/12/98	Zafar	438	3	
	AG	5,811,847	09/22/98	Joshi et al.	257	296	
	AH	5,864,153	01/26/99	Nagel et al.	257	296	
	AI	5,956,594	09/21/99	Yang et al.	438	396	
TH	AJ	5,965,942	12/12/99	Itoh et al.	257	761	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
TH	AK	0793274A1	09/03/97	EP	X	
	AL	WO 98/05071	02/05/98	WIPO		
	AM	19640246A1	04/02/98	DE		X
	AN	0 837 504 A2	04/22/98	EP		
TH	AO	0 996 160 A1	06/26/00	EP		

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

TH	AP	Yamazaki, T. et al., "Advanced 0.5µm FRAM Device Technology with Full Compatibility of Half-Micron CMOS Logic device", IEEE, pp. 25.5.1-25.5.4, XP000855871, December 1997.
	AQ	
	AR	

EXAMINER

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May 2 2004

* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).

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TH	AA	5,973,342	10/26/99	Nakamura	257	295	
	AB	5,981,382	11/09/99	Konecni et al.	438	646	
	AC	5,990,507	11/23/99	Mochizuki et al.	257	295	
	AD	5,994,153	11/30/99	Nagel et al.	438	3	
	AE	5,998,296	12/07/99	Saran et al.	438	685	
	AF	6,037,252	03/14/00	Hillman et al.	438	637	
	AG	6,043,529	03/28/00	Hartner et al.	257	306	
	AH	6,051,858	04/18/00	Uchida et al.	257	295	
	AI	6,075,264	06/13/00	Koo	257	295	
TH	AJ	6,091,599	07/18/00	Amamiya	361	306.3	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
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THP	AA	6,121,083	09/19/00	Matsuki	438	254	
	AB	6,180,974	01/30/01	Okutoh et al.	257	306	
	AC	6,194,311	02/27/01	Nakajima	438	660	
	AD	6,197,631	03/06/01	Ishihara	438	240	
	AE	6,239,460	05/29/01	Kuroiwa et al.	257	300	
	AF	6,281,537	08/28/01	Kim	257	295	
THP	AG	6,313,539	11/06/01	Yokoyama et al.	257	761	
	AH						
	AI						
	AJ						

FOREIGN PATENT DOCUMENTS

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